



4th IEEE International Workshop on Silicon Debug and Diagnosis - SDD07

Dorint Hotel, Freiburg, Germany

May 23rd-24th, 2007

Held in conjunction with the [IEEE European Test Symposium 2007](#)

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Call for Papers

Scope and Mission

Troubleshooting how and why systems and circuits fail is important and is rapidly growing in industry significance. Debug and diagnosis may be needed for yield improvement, process monitoring, correcting the design function, failure mode learning for R&D, or just getting a working first prototype. This detective work can however become very tricky. Sources of difficulty include circuit and system complexity, packaging, limited physical access, shortened product creation cycle and time-to-market, the traditional focus on only pass/fail testing and missing tool and equipment capabilities. New and efficient solutions for debug and diagnosis will have a much needed and highly visible impact on productivity. The mission and objective of the SDD07 Workshop is to consider all issues related to debug and diagnosis of systems and circuits – from prototype bring-up to volume production.

The topics of interest include, but are not limited to, the following:

Debug Techniques and Methodologies

Design and Synthesis for Debug

DFT Reuse for Debug and Diagnosis

Methods & Tools

Equipment Impact and Techniques

Debug Standardization

Structured Debug Architectures

Microprocessor Debug

Debug of Embedded Cores/SoCs

System Level Debug & Diagnosis

Manufacturing & Prototype Environment

Debug Case Studies

Infrastructure IP for SDD

Debug for FPGAs

Digital/analog Turn-on

Author Information

The workshop objective is to facilitate a valuable interactive information exchange. Contributions ranging from extended abstracts to full papers are acceptable for submission. Contributions that provide more detail have a higher chance of being accepted. Proposals that describe open issues, industry/technology needs or opinions are also welcome.

– Length Guideline: ranging from a one page, extended abstract up to 8 pages

– Submissions due: March 7th

– Acceptance Notification: March 28th

– Final papers for inclusion into informal proceedings: April 18th

Proposals for discussion panels and other special sessions are also invited. Please submit a one page abstract for these to the web site or contact the Program Chair.

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SDD07 is sponsored by the IEEE Computer Society Test Technology Technical Council.

For more information on SDD07, visit the website at: <http://evia.ucsd.edu/conferences/sdd/07>

